## IN THE TITLE:

Please amend the title as follows:

METHOD AND EQUIPMENT FOR JUDGING TARGET BY TERA HELTZ WAVE
SPECTROMETRYMETHOD AND APPARATUS FOR INSPECTING TARGET BY
TERA-HERTZ WAVE SPECTROMETRY

## **IN THE SPECIFICATION**:

Page 1, immediately beneath the title, please insert the following new paragraph:

This is a National Phase Application in the United States of International Patent Application No. PCT/JP2004/003634 filed March 18, 2004, which claims priority on Japanese Patent Application No. 082466/2003, filed March 25, 2003 The entire disclosures of the above patent applications are hereby incorporated by reference.